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Neural Network (RNN). The review provides researchers with some guidelines for future research on this topic.

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I. Introduction

Sudden Cardiac Death (SCD) is a leading cause of mortality and although data from many regions to the world is limited, SCD remains a major public health burden worldwide [1], accounting 50% of deaths form cardiovascular disease and approximately 350.000 annual deaths in the United States [2] [3]. In [1] suggest that men have a three to four-

fold higher risk for Scd compared woman. SCD Risk Factors is (1) age, sex, and ethnicity, (2) clinical risk factors, (3) coronary heart disease, (4) other structural heart disease, (5) Inherited arrhythmic disorder, and (6) electrocardiogram (ECG) parameters [1].

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